

CERTIFICATE OF ANALYSIS

ERM[®]-EB101a

PbCaSnAl

Certified Values			
	Certified value ¹⁾	Uncertainty ²⁾	
Element	Mass fraction in %		
Ca	0.136	±	0.007
Sn	0.294	±	0.006
Al	0.0227	±	0.0009
Element	Mass fraction in mg/kg		
Ag	29.0	±	1.1
Bi	165	±	7
Cu	24.3	±	1.1
Tl	10.2	±	0.6
Zn	1.0	±	0.8
<p>¹⁾ Unweighted mean value of the means of accepted sets of data, each set being obtained in a different laboratory and/or with a different method of measurement. The values are traceable to the SI (Système International d'Unités) via calibration using pure metals or substances of known stoichiometry.</p> <p>²⁾ Estimated expanded uncertainty <i>U</i> with a coverage factor of <i>k</i>=2, corresponding to a level of confidence of approx. 95 %, as defined in the Guide to the expression of uncertainty in measurement, ISO, 1993.</p>			

This certificate is valid until 10/2059; this validity may be extended as further evidence of stability becomes available.

DESCRIPTION OF THE SAMPLE

The Reference Material is available in the form of discs (40 mm diameter and 40 mm height). It is intended for establishing and checking the calibration of optical emission and X-ray spectrometers (excluding micro-analysis) for the analysis of samples of similar materials.

NOTE

European Reference Material ERM[®]-EB101a was produced and certified under the responsibility of BAM Federal Institute for Materials Research and Testing in cooperation with the Committee of Chemists of the GDMB, Gesellschaft für Bergbau, Metallurgie, Rohstoff- und Umwelttechnik according to the principles laid down in the technical guidelines of the European Reference Materials[®] co-operation agreement between BAM-LGC-IRMM. Information on these guidelines is available on the Internet (<http://www.erm-crm.org>).

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BAM Department I
Analytical Chemistry;
Reference Materials
12200 Berlin, Germany

BAM Division I.1
Inorganic Chemical Analysis;
Reference Materials
12200 Berlin, Germany

Prof. Dr. U. Panne
(Head of Department)

Dr. N. Jakubowski
(Head of Division)

Indicative Values¹⁾		
	Indicative value	Uncertainty
Element	Mass fraction in mg/kg	
As	< 2	
Ni	< 0.6	
P	< 3	
Sb	< 1.2	

¹⁾ Values were not certified, but given as indicative values, when the number of accepted data sets was considered to be too low (< 5), when the uncertainty from the inter-laboratory certification was considerably larger than the expected range or when only an upper limit can be given.

Additional Material Information¹⁾		
	Mean or upper limit	Std.-dev ²⁾
Element	Mass fraction in mg/kg	
Cd	< 2	
Fe	< 2	
Mg	9	± 1
Na	4	± 1
S	< 3	
Te	< 3	

¹⁾ Values were obtained in an interlaboratory comparison with spark emission spectrometry.

²⁾ Standard deviation calculated from the mean of means of the interlaboratory comparison with n = 6 for Cd and Fe, n = 4 for Mg, n = 7 for Na, n = 12 for S and n = 11 for Te.

MEANS OF ACCEPTED DATA SETS

Certified values

Mass fraction in %

Mass fraction in mg/kg

Indicative values

Mass fraction in mg/kg

Line no.	Ca	Sn	Al	Ag	Bi	Cu	Tl	Zn		As	Ni	P	Sb
1	0.133	---	0.0217	26.4	153	23.0	8.63	0.51		0.08	0.05	0.18	0.62
2	0.134	0.281	0.0220	26.7	156	23.2	9.50	0.60		0.10	0.07	0.27	0.62
3	0.135	0.283	0.0223	27.9	160	23.6	9.67	0.88		0.19	0.08	0.80	0.66
4	0.136	0.289	0.0225	28.0	162	23.8	9.92	0.94		0.30	0.11	1.05	0.87
5	0.136	0.290	0.0226	28.9	162	24.1	10.11	1.00		0.54	0.32	2.73	0.91
6	0.137	0.294	0.0230	29.0	163	24.3	10.23	1.10		1.00	0.59	< 5	1.10
7	0.138	0.294	0.0228	29.4	167	24.4	10.75	1.17		1.53	< 0.5		1.12
8	0.138	0.294	0.0229	29.4	167	24.5	10.75	1.38		< 1	< 0.5		< 1
9	0.138	0.297	0.0229	29.6	168	24.5	11.19	---			< 1		---
10	0.138	0.298	0.0230	29.9	170	24.7	11.34				< 1		---
11	0.140	0.300	0.0233	30.5	173	24.7							
12		0.302	0.0233	30.5	175	25.0							
13		0.304		30.6		25.3							
14						25.7							
15													
M :	0.136	0.294	0.0227	29.0	165	24.3	10.2	0.95		0.534	0.201	1.22	0.84
s_M :	0.002	0.008	0.0005	1.4	7	0.8	0.9	0.29		0.544	0.214	1.062	0.22
s_i :	0.002	0.003	0.0004	0.3	3	0.5	0.5	0.12		0.106	0.070	0.328	0.09

The laboratory mean values have been examined statistically to eliminate outlying values. Each laboratory mean consists of at least 4 but usually 6 single values. Where " --- " appears in the table it indicates that an outlying value has been omitted (Grubbs 99 %). " < "-values have not been considered in statistical evaluation.

M : mean of means of data sets

\bar{s}_i : mean of standard deviations of data sets under repeatability conditions

s_M : standard deviation of means of data sets

TECHNICAL REPORT

A detailed technical report (in German) describing the analysis procedures and the treatment of the analytical data used to certify ERM[®]-EB101a is available on request.

ANALYTICAL METHOD USED FOR CERTIFICATION

Element	Line no.	Method
Ca	1, 2, 3, 4, 6, 9, 10, 11	ICP-OES
	5, 7, 8	FAAS
Sn	2, 3, 5, 7, 8, 9, 10, 11, 12, 13	ICP-OES
	4, 6	FAAS
Al	1, 2, 3, 4, 5, 6, 9, 10, 11, 12	ICP-OES
	7, 8	FAAS
Bi	1, 2, 3, 6, 8, 9, 10, 11, 12	ICP-OES
	4, 5	FAAS
	7	ICP-MS
Ag	1	ICP-OES after separation of the matrix
	2, 3, 4, 6, 8, 11, 13	ICP-OES
	5	ICP-MS
	7	FAAS after separation of the matrix
	9, 10, 12	FAAS
Cu	2, 5, 15	FAAS
	3, 7	ICP-MS
	4, 6, 8, 9, 10, 11, 12, 13, 14	ICP-OES
Tl	1, 3, 5, 9, 10	ICP-OES
	2	ICP-OES after separation of the matrix
	4, 6	ICP-MS
	7, 8	FAAS
Zn	1, 2, 4, 7, 8	ICP-OES
	3	ICP-MS
	5	FAAS
	6	ICP-OES after separation of the matrix
As	1, 4, 5, 7	ICP-OES
	2	ICP-OES after separation of the matrix
	3, 8	ICP-MS
	6	Spectrophotometry
Ni	1, 2	ICP-OES after separation of the matrix
	3, 4, 6	ICP-OES
	5, 10	ICP-MS
	7, 9	FAAS
	8	ETAAS
P	1, 3, 5, 6	ICP-OES
	2	ICP-OES after separation of the matrix
	4	Spectrophotometry
Sb	1	ETAAS
	2, 3, 5, 7	ICP-OES
	4, 8	ICP-MS
	6	FAAS

Abbreviations:

ICP-OES:	Inductively coupled plasma optical emission spectrometry
ICP-MS:	Inductively coupled plasma mass spectrometry
FAAS:	Flame atomic absorption spectrometry
ETAAS:	Electrothermal atomic absorption spectrometry

INTENDED USE

The CRM is intended for establishing and checking the calibration of optical emission and X-ray spectrometers (excluding micro-analysis) for the analysis of samples of similar materials. The minimum sample size for wet chemical analysis is 0.5 g.

INSTRUCTIONS FOR USE

Before use, the surface of the material must be prepared by milling or turning on a lathe.

STORAGE

The material should be stored in a dry and clean environment at room temperature.

PARTICIPANTS

Aurubis AG, Hamburg, Germany
BAM Bundesanstalt für Materialforschung und -prüfung, Berlin, Germany
BERZELIUS Stolberg GmbH, Stolberg, Germany
BSB Recycling GmbH, Braubach, Germany
Exide Technologies GmbH, Bad Lauterberg, Germany
GfE Fremat GmbH, Freiberg, Germany
Johnson Controls Sachsen-Batterien GmbH & Co. KG, Zwickau, Germany
Johnson Controls Power Solutions Europe, Guardamar del Segura, Spain
Johnson Controls, VB Autobatterie GmbH & Co. KGaA, Hannover, Germany
Muldenhütten Recycling und Umwelttechnik GmbH, Freiberg, Germany
Nyrstar, Overpelt, Belgium
ThyssenKrupp Steel AG, Duisburg, Germany
TU Bergakademie Freiberg, Freiberg, Germany
WESER-METALL GmbH, Nordenham, Germany

Supply of Reference Materials by: **BAM Bundesanstalt für Materialforschung und -prüfung**

Richard-Willstätter-Straße 11, 12489 Berlin, Germany

Phone: +49 30 8104 2061

e-mail: sales.crm@bam.de

Fax: +49 30 8104 1117

internet: www.bam.de